

<b>Notice of References Cited</b>	Application/Control No. 10/082,176	Applicant(s)/Patent Under Reexamination HASEGAWA, TOSHITAKA	
	Examiner Rehana Perveen	Art Unit 2116	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0065961 A1	04-2003	Koenen, David J.	713/323
	B	US-6,741,442 B1	05-2004	McNally et al.	361/166
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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